

Supplementary Materials

Simulation of optical nano-manipulation with metallic single- and dual-probe irradiated by polarized near-field laser

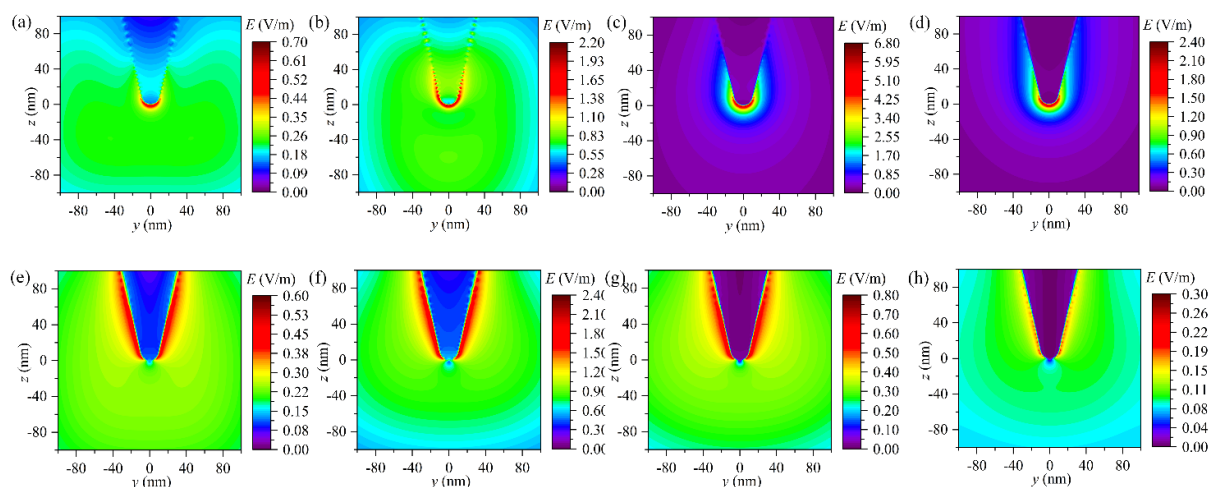


Figure S1. Distributions of electric field in y - z plane induced by polarized laser with different wavelengths. VP and HP laser with wavelength of 300nm (a) and (e), 511nm (b) and (f), 918nm (c) and (g), and 1200 nm (d) and (h).

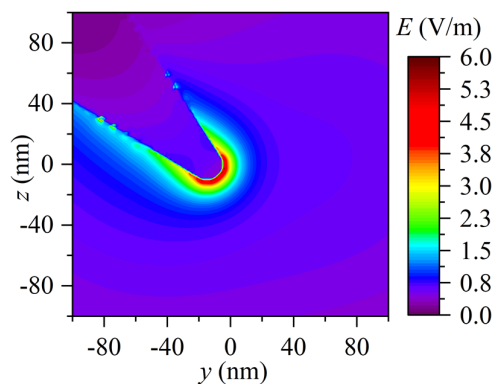


Figure S2. Distributions of electric field in y - z plane for the configuration of ODPs with only one probe irradiated by HP laser with wavelengths 717 nm.

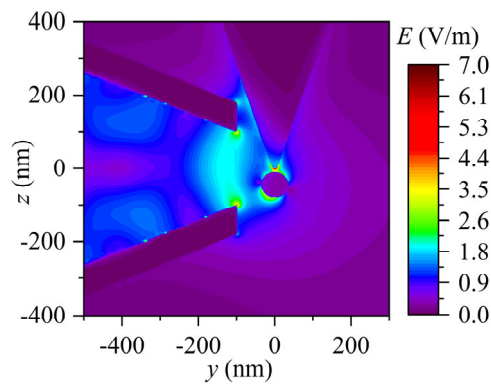


Figure S3. Distributions of electric field in y - z plane induced by VP laser with wavelengths 511 nm.

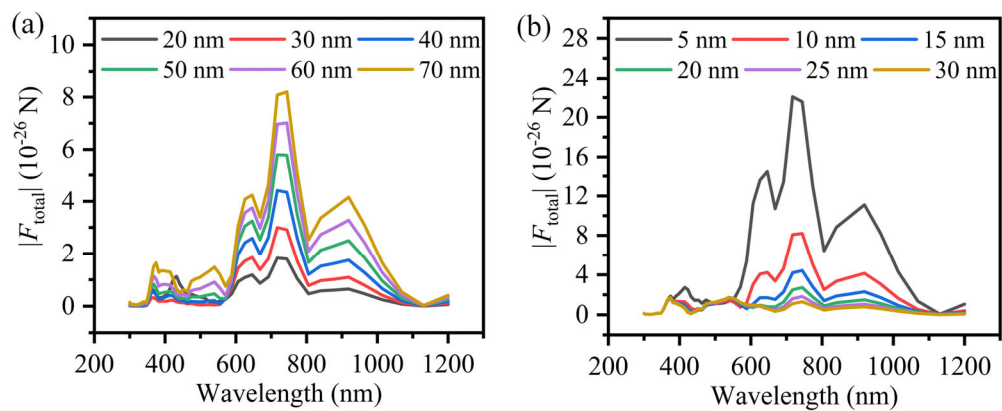


Figure S4. The influence of diameter of NP and distance between the tip and the NP on the total optical force. (a) Diameter; (b) Distance.

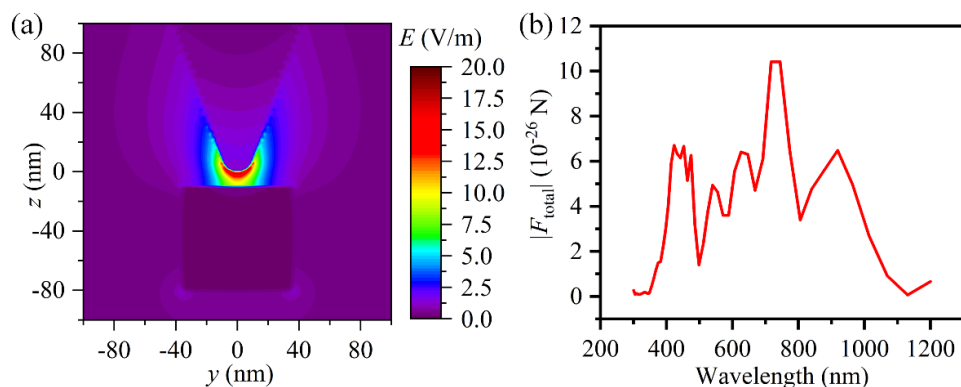


Figure S5. Trapping force of a nano-cube using single probe irradiated by VP laser. (a) Distributions of electric field in y - z plane; (b) Total optical force applied on the nano-cube versus wavelength of incident laser;

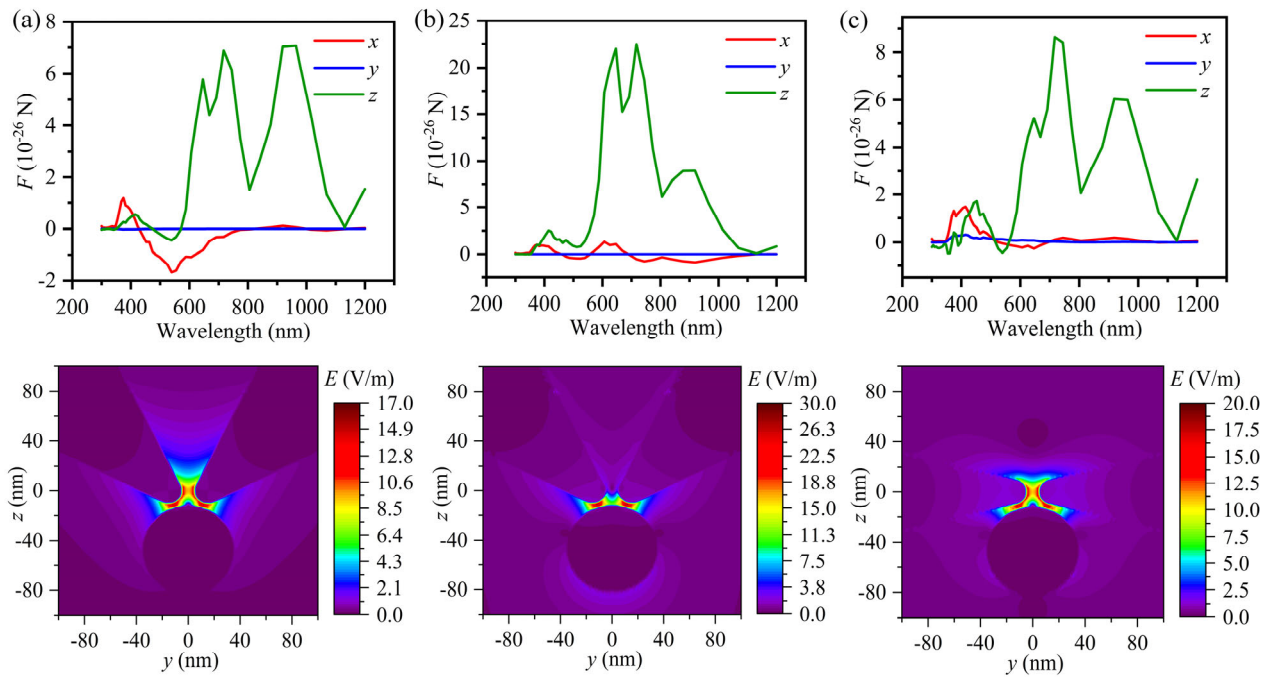


Figure S6. Component forces along x, y, z axis applied on the NP versus wavelength (top diagram) and distributions of electric field in y-z plane (bottom diagram) around dual-probe with distance $D_2 = 5$ nm between tips and NP. (a) ODPs irradiated by HP laser; (b) ODPs irradiated by VP laser; (c) CDPs irradiated by HP laser.